









SCLS425H - JUNE 1998 - REVISED JULY 2024



SN74AHC174 Hex D-Type Flip-Flops With Clear

1 Features

- Operating range 2V to 5.5V V_{CC}
- Contain six flip-flops with single-rail outputs
- 3. Latch-up performance exceeds 250mA per JESD 17

2 Applications

- **Buffer/Storage Registers**
- Shift Registers
- **Pattern Generators**

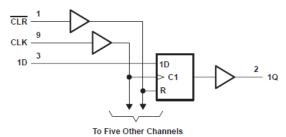
3 Description

The 'AHC174 devices are positive-edge-triggered Dtype flip-flops with a direct clear (CLR) input and are designed for 2V to 5.5V V_{CC} operation.

Package Information

	•		
PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE(2)	BODY SIZE(3)
SN74AHC174	D (SOIC, 16)	9.9mm × 6mm	9.9mm × 3.9mm
	DB (SSOP, 16)	6.2mm × 7.8mm	6.2mm × 5.3mm
SIN/4AHC1/4	N (PDIP, 16)	19.3mm × 9.4mm	19.3mm × 6.35mm
	PW (TSSOP, 16)	5mm × 6.4mm	5mm × 4.4mm

- For more information, see Mechanical, Packaging, and Orderable Information.
- The package size (length × width) is a nominal value and includes pins, where applicable.
- The body size (length × width) is a nominal value and does not include pins.



Logic Diagram (Positive Logic)



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4 Pin Configuration and Functions

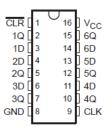


Figure 4-1. D, DB, DGV, N, NS, or PW Package (Top View)

Table 4-1. Pin Functions

	PIN		DESCRIPTION
NAME	NO.	TYPE	DESCRIPTION
CLR	1	I	Clear Pin
1Q	2	0	1Q Output
1D	3	I	1D Input
2D	4	I	2D Input
2Q	5	0	2Q Output
3D	6	I	3D Input
3Q	7	0	3Q Output
GND	8	_	Ground Pin
CLK	9	I	Clock Pin
4Q	10	0	4Q Output
4D	11	I	4D Input
5Q	12	0	5Q Output
5D	13	I	5D Input
6D	14	I	6D Input
6Q	15	0	6Q Output
V _{CC}	16	Р	Power Pin



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage	Supply voltage			V
V _I ⁽²⁾	Input voltage	Input voltage			V
V _O ⁽²⁾	Output voltage	Output voltage			V
I _{IK}	Input clamp current	(V _I < 0)		-20	mA
I _{OK}	Output clamp current	(V _O < 0)		±20	mA
Io	Continuous output current	$(V_O = 0 \text{ to } V_{CC})$		±25	mA
	Continuous current through V _{CC} or GND			±50	mA
T _{stg}	Storage temperature range	Storage temperature range		150	°CW

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 ESD Ratings

			VALUE	UNIT
V		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 (1)	±2000	V
(ESD)	V _(ESD) Electrostatic discharge	Charged-device model (CDM), per ANSI/ESDA/JEDEC JS-002 (2)	±1000	V

¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)(1)

			MIN	MAX	UNIT	
V _{CC}	Supply voltage		2	5.5	V	
		V _{CC} = 2 V	1.5			
V_{IH}	High-level input voltage	V _{CC} = 3 V	2.1		V	
		V _{CC} = 5.5 V	3.85			
		V _{CC} = 2 V		0.5		
V_{IL}	Low-level input voltage	V _{CC} = 3 V		0.9	V	
		V _{CC} = 5.5 V		1.65		
VI	Input voltage	0	5.5	V		
Vo	Output voltage		0	V _{CC}	V	
		V _{CC} = 2 V		-50	μA	
I _{OH}	High-level output current	V _{CC} = 3.3 V ± 0.3 V		-4	mA	
		V _{CC} = 5 V ± 0.5 V		-8		
		V _{CC} = 2 V		50	μA	
I _{OL}	Low-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		4	A	
		$V_{CC} = 5 V \pm 0.5 V$		8	mA	
Λ+/Λ·	Input transition vice or fellt-	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		100		
Δt/Δv	Input transition rise or fall rate	V _{CC} = 5 V ± 0.5 V		20	ns/V	
T _A	Operating free-air temperature		-40	85	°C	

All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs.

Product Folder Links: SN74AHC174

⁽²⁾ The input and output negative-voltage ratings may be exceeded if the input and output damp current ratings are observed.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



5.4 Thermal Information

		SN74AHC174						
	THERMAL METRIC ⁽¹⁾	D	DB	DGV	N	NS	PW	UNIT
16 PINS								
R _{θJA}	Junction-to-ambient thermal resistance	73	82	120	67	64	135.9	°C/W

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report (SPRA953).

5.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	T _A = 25°C			SN74AHC174		UNIT
PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	MIN	MAX	UNII
V _{OH}		2 V	1.9	2		1.9		
	I _{OH} = -50 μA	3 V	2.9	3		2.9		
		4.5 V	4.4	4.5		4.4		V
	I _{OH} = -4 mA	3 V	2.58			2.48		V
	I _{OH} = -8 mA	4.5 V	3.94			3.8		
		2 V			0.1		0.1	
	I _{OL} = 50 μA	3 V			0.1		0.1	
V _{OL}		4.5 V			0.1		0.1	V
	I _{OL} = 4 mA	3 V			0.36		0.44	V
	I _{OL} = 8 mA	4.5			0.36		0.44	
I _I	V _I = 5.5 V or GND	0 V to 5.5 V			± 0.1		±1	μA
Icc	V _I = V _{CC} or GND, I _O = 0	5.5 V			4		40	μA
Ci	V _I = V _{CC} or GND	5 V		1.7	10		10	pF

5.6 Timing Requirements, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range (unless otherwise noted)

	, 5	1 3 \		,				
			T _A = 25°	С	SN74AHC174		UNIT	
			MIN	MAX	MIN	MAX	ONIT	
t _w Pulse duration	CLR low	5		5				
	Fuise duration	CLK high or low	5		5		ns	
	Setup time before CLK↑	Data	5		6		-	
l _{su} Setup time b	Setup time before CLK	CLR inactive	3		3		ns	
t _h	Hold time, data after CLK↑		0		0		ns	

5.7 Timing Requirements, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range (unless otherwise noted)

			T _A = 25°C		SN74AHC174		UNIT
			MIN	MAX	MIN	MAX	ONII
	t _w Pulse duration	CLR low	5		5		no
t _w	Fuise duration	CLK high or low	5		5		ns
	Setup time before	Data	4.5		4.5		no
t _{su}	CLK↑	CLR inactive	2.5		2.5		ns
t _h	Hold time, data after CLK↑		0.5		0.5		ns

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5.8 Switching Characteristics, $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	FROM	TO LOAI	LOAD	T _A = 25°C			SN74AHC174		UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNII
f _{max}			C _L = 15 pF	95 ¹	170 ¹		80		MHz
			C _L = 50 pF	55	130		50		IVITZ
t _{PHL}	CLR	Any Q	C _L = 15 pF		4.5 ¹	11.4 ¹	1	13.5	ns
t _{PLH}	CLK	LK Any Q	C _L = 15 pF		5.8 ¹	11 ¹	1	13	ns
t _{PHL}	CLK	Ally Q	CL = 15 pr		5.8 ¹	11 ¹	1	13	115
t _{PHL}	CLR	Any Q	C _L = 50 pF		6	14.9	1	17	ns
t _{PLH}	CLK	Any Q	0 50 5		7.5	14.5	1	16.5	ns
t _{PHL}	CLK Any	Any Q $C_L = 50 \text{ pF}$		7.5	14.5	1	16.5	115	
t _{sk(o)}			C _L = 50 pF			1.5 ²		1.5	ns

- 1. On products compliant to MIL-PRF-38535, this parameter is not production tested.
- 2. On products compliant to MIL-PRF-38535, this parameter does not apply.

5.9 Switching Characteristics, $V_{CC} = 5 V \pm 0.5 V$

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	FROM	то	LOAD	T _A = 25°C			SN74AHC174		UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	UNII
f _{max}			C _L = 15 pF	130 ¹	240 ¹		110		MHz
			C _L = 50 pF	90	180		80		IVII IZ
t _{PHL}	CLR	Any Q	C _L = 15 pF		3 ¹	7.6 ¹	1	9	ns
t _{PLH}	CLK	Any Q	C _L = 15 pF		4.1 ¹	7.2 ¹	1	8.5	ns
t _{PHL}	OLK	Ally Q	OL - 13 pi		4.1 ¹	7.2 ¹	1	8.5	115
t _{PHL}	CLR	Any Q	C _L = 50 pF		4.2	9.6	1	11	ns
t _{PLH}	CLK	Any Q	C _L = 50 pF		5.5	9.2	1	10.5	ns
t _{PHL}		Ally Q	C[- 30 βi		5.5	9.2	1	10.5	115
t _{sk(o)}			C _L = 50 pF			1 ²		1	ns

- 1. On products compliant to MIL-PRF-38535, this parameter is not production tested.
- 2. On products compliant to MIL-PRF-38535, this parameter does not apply.

5.10 Operating Characteristics

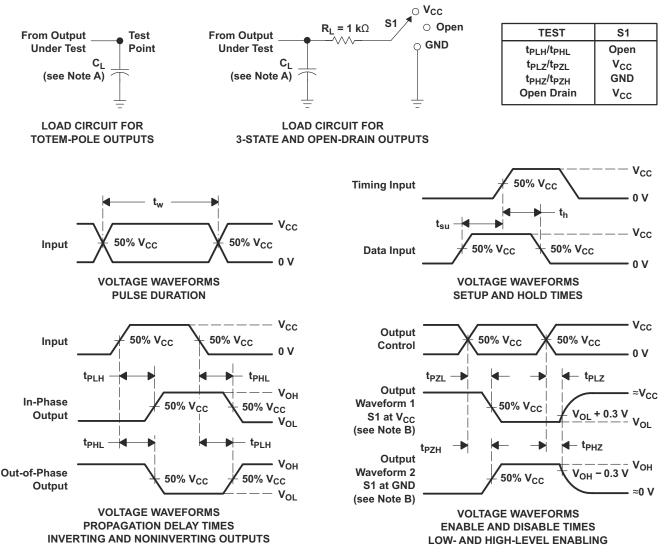
 $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C	Power dissipation capacitance	No load, f = 10 MHz	15.2	pF

Product Folder Links: SN74AHC174



6 Parameter Measurement Information



- A. C_L includes probe and jig capacitance.
- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r \leq 3$ ns. $t_r \leq 3$ ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
- F. t_{PZL} and t_{PZH} are the same as t_{en}.
- G. t_{PHL} and t_{PLH} are the same as t_{pd} .
- H. All parameters and waveforms are not applicable to all devices.

Figure 6-1. Load Circuit and Voltage Waveforms

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7 Detailed Description

7.1 Overview

Information at the data (D) inputs that meets the setup time requirements is transferred to the outputs on the positive-going edge of the clock (CLK) pulse. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going edge of CLK. When CLK is at either the high or low level, the D input has no effect at the output.

7.2 Functional Block Diagram

Figure 7-1. Logic Diagram (Positive Logic)

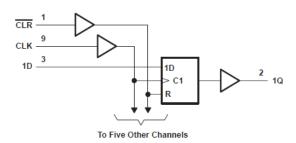


Figure 7-2.

7.3 Device Functional Modes

Table 7-1. Function Table

	INPUTS(1)	OUTPUT							
CLR	CLK	D	Q						
L	Х	Х	L						
Н	1	Н	Н						
Н	1	L	L						
Н	L	Х	Qo						

H = High Voltage Level, L = Low Voltage Level, X = Do not Care, Z = High Impedance

Product Folder Links: SN74AHC174



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- μ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. The 0.1- μ F and 1- μ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results, as shown in the following layout example.

8.2 Layout

8.2.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices, inputs must never be left floating. In many cases, functions or parts of functions of digital logic devices are unused (for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used). Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or V_{CC} , whichever makes more sense for the logic function or is more convenient.

8.2.2 Layout Example

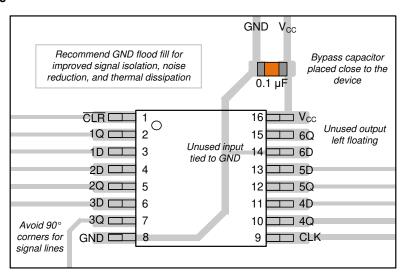


Figure 8-1. Layout Example of the



9 Device and Documentation Support

9.1 Documentation Support (Analog)

9.1.1 Related Documentation

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 9-1. Related Links

PARTS	PRODUCT FOLDER	SAMPLES RIV		TOOLS & SOFTWARE	SUPPORT & COMMUNITY	
SN74AHC1G04-Q1	Click here	Click here	Click here	Click here	Click here	

9.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on Notifications to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.3 Support Resources

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.4 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

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9.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications

9.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision G (November 2023) to Revision H (July 2024)

Page

Changes from Revision F (June 1998) to Revision G (November 2023)

Page

Added Applications section, Package Information table, Pin Functions table, ESD Ratings table, Thermal Information table, Device Functional Modes, Device and Documentation Support section, and Mechanical,

Product Folder Links: SN74AHC174



11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN74AHC174D	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI	-40 to 85	AHC174	
SN74AHC174DBR	ACTIVE	SSOP	DB	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA174	Samples
SN74AHC174DR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	AHC174	Samples
SN74AHC174N	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74AHC174N	Samples
SN74AHC174PWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HA174	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and



PACKAGE OPTION ADDENDUM

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continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74AHC174DBR	SSOP	DB	16	2000	330.0	16.4	8.35	6.6	2.4	12.0	16.0	Q1
SN74AHC174DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74AHC174PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74AHC174DBR	SSOP	DB	16	2000	356.0	356.0	35.0
SN74AHC174DR	SOIC	D	16	2500	340.5	336.1	32.0
SN74AHC174PWR	TSSOP	PW	16	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN74AHC174N	N	PDIP	16	25	506	13.97	11230	4.32
SN74AHC174N	N	PDIP	16	25	506	13.97	11230	4.32

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.





NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.







- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-150.





NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.



N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



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